## Notice of References Cited Application/Control No. 10/659,159 Examiner Wayne Langel Applicant(s)/Patent Under Reexamination TRAN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	. Name	Classification
	Α	US-6,764,665	07-2004	Deeba et al.	423/239.1
	В	US-6,660,683	12-2003	Yaluris et al.	502/241
	С	US-6,677,264	01-2004	Klein et al.	502/74
	۵	US-6,849,572	02-2005	Hwang et al.	502/325
	Е	US-7,022,646	04-2006	Li, Yuejin	502/339
	⊩	US-4,617,289	10-1986	Saito et al.	502/339
	G	US-4,077,913	03-1978	Acres et al.	502/302
	Ι	US-			
	-	US-			
	7	US-			
	Κ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				,1	
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
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	×	

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